

Reliability Summary Report

Product Type: 256GB uSD

Capacity	Part Number
256GB	KTUDEGA1AWIT1

1. Product Information

Product No.	Dimensions	JEDEC Standard
KTUDEGA1AWIT1	11 x 15 x 1 mm	SD v6.1

2. Test Summary

Product Test Result				
<input checked="" type="checkbox"/> PASS <input type="checkbox"/> FAIL				
	Test Items	Test Results		Notes
1	Performance	<input checked="" type="checkbox"/> PASS	<input type="checkbox"/> FAIL	
2	Electrical Performance	<input checked="" type="checkbox"/> PASS	<input type="checkbox"/> FAIL	
3	Reliability	<input checked="" type="checkbox"/> PASS	<input type="checkbox"/> FAIL	

3. Performance

3.1. Crystal-Disk Mark Benchmark V5.0.2

Capacity	Sequential (Q32T1)		Random 4KB (Q32T1)		Sequential		Random 4KB	
	Read	Write	Read	Write	Read	Write	Read	Write
256GB	96.58	79.72	14.09	3.415	96.27	97.28	12.08	3.408

(Unit : MB/s)

3.2. TestMetrix_Performance

Capacity	Sequential Read (MB/s)	Sequential Write (MB/s)	Random Read 4KB (IOPS)	Random Write 4KB (IOPS)
256GB	97	80	9400	7200

(1) Sequential performance measured using Crystal Disk. Random performance measured using TestMetrix A2 Test script.

4. Electrical Performance

4.1. Power Consumption

Parameter	Max.	Unit (Typical)
Write	215	mA
Read	175	mA
Standby	0.5	mA

(1) The testing result is measured by Crystal Disk Mark 5.1.2

(2) The measurement may vary among different host systems and settings.

5. Reliability

Test Item	Test Reference	Sample Size	Test Result
High Temperature Operation Test	IEC 60068-2-2	5	Pass
Low Temperature Operation Test	IEC 60068-2-1	5	Pass
Bending Test	SDA SPEC.	5	Pass
Torque Test	SDA SPEC.	3	Pass
Drop Test	SDA SPEC.	3	Pass
Durability Test	EIA 364-13	3	Pass
Salt Spray Test	MIL STD-883 Method 1009	5	Pass